Applicant(s)/Patent Under Application/Control No. Reexamination 10/822,706 SENOH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sean Kayes 2841 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,323,444 11-2001 Aoki, Hiroshi 177/144 Α US-В С US-US-D Ε US-F US-G US-US-Н US-US-J US-Κ L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q

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